

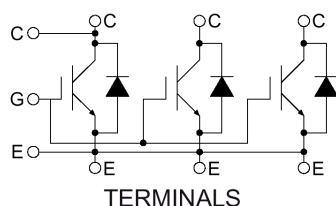
MBN1200E33D

Silicon N-channel IGBT

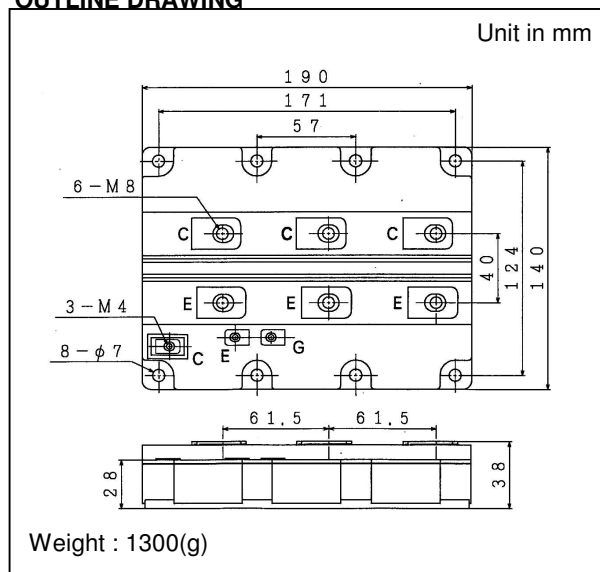
FEATURES

- * High speed, low loss IGBT module.
- * Low driving power due to low input capacitance MOS gate.
- * Low noise due to ultra soft fast recovery diode.
- * High reliability, high durability module.
- * High thermal fatigue durability.
($\Delta T_c=70^\circ\text{C}$, $N>30,000$ cycles)
- * Isolated head sink (terminal to base).

CIRCUIT DIAGRAM



OUTLINE DRAWING



ABSOLUTE MAXIMUM RATINGS ($T_c=25^\circ\text{C}$)

| Item | Symbol | Unit | MBN1200E33D |
|---------------------------|-------------------|------------------|--------------------|
| Collector Emitter Voltage | V_{CES} | V | 3,300 |
| Gate Emitter Voltage | V_{GES} | V | ± 20 |
| Collector Current | DC | I_C | 1,200 |
| | 1ms | I_{Cp} | 2,400 |
| Forward Current | DC | I_F | 1,200 |
| | 1ms | I_{FM} | 2,400 |
| Junction Temperature | T_j | $^\circ\text{C}$ | -40 ~ +125 |
| Storage Temperature | T_{stg} | $^\circ\text{C}$ | -40 ~ +125 |
| Isolation Voltage | V_{ISO} | V_{RMS} | 6,000(AC 1 minute) |
| Screw Torque | Terminals (M4/M8) | - | 2/10 (1) |
| | Mounting (M6) | - | 6 (2) |

Notes: (1) Recommended Value $1.8\pm 0.2/9\pm 1\text{N}\cdot\text{m}$ (2) Recommended Value $5.5\pm 0.5\text{N}\cdot\text{m}$

ELECTRICAL CHARACTERISTICS

| Item | Symbol | Unit | Min. | Typ. | Max. | Test Conditions |
|--------------------------------------|-----------------|---------------|------|-------|--------|---|
| Collector Emitter Cut-Off Current | I_{CES} | mA | - | - | 12 | $V_{CE}=3,300\text{V}$, $V_{GE}=0\text{V}$, $T_j=25^\circ\text{C}$ |
| | | | - | 20 | 60 | $V_{CE}=3,300\text{V}$, $V_{GE}=0\text{V}$, $T_j=125^\circ\text{C}$ |
| Gate Emitter Leakage Current | I_{GES} | nA | -500 | - | +500 | $V_{GE}=\pm 20\text{V}$, $V_{CE}=0\text{V}$, $T_j=25^\circ\text{C}$ |
| Collector Emitter Saturation Voltage | $V_{CE(sat)}$ | V | - | 4.2 | 5.2 | $I_C=1,200\text{A}$, $V_{GE}=15\text{V}$, $T_j=125^\circ\text{C}$ |
| Gate Emitter Threshold Voltage | $V_{GE(TO)}$ | V | 4.5 | 6.0 | 7.0 | $V_{CE}=10\text{V}$, $I_C=1,200\text{mA}$, $T_j=25^\circ\text{C}$ |
| Input Capacitance | C_{ies} | nF | - | 110 | - | $V_{CE}=10\text{V}$, $V_{GE}=0\text{V}$, $f=100\text{kHz}$, $T_j=25^\circ\text{C}$ |
| Internal Gate Resistance | R_{ge} | Ω | - | 1.2 | - | $V_{CE}=10\text{V}$, $V_{GE}=0\text{V}$, $f=100\text{kHz}$, $T_j=25^\circ\text{C}$ |
| Switching Times | Rise Time | t_r | - | 1.9 | 3.1 | $V_{CC}=1,650\text{V}$, $I_C=1,200\text{A}$ |
| | Turn On Time | t_{on} | - | 2.4 | 3.3 | $L=100\text{nH}$ |
| | Fall Time | t_f | - | 1.0 | 2.5 | $R_G=3.3\Omega$ (3) |
| | Turn Off Time | t_{off} | - | 3.0 | 5.1 | $V_{GE}=\pm 15\text{V}$, $T_j=125^\circ\text{C}$ |
| Peak Forward Voltage Drop | V_{FM} | V | - | 2.5 | 3.0 | $I_F=1,200\text{A}$, $V_{GE}=0\text{V}$, $T_j=125^\circ\text{C}$ |
| Reverse Recovery Time | t_{rr} | μs | - | 0.6 | 1.1 | $V_{CC}=1,650\text{V}$, $I_F=1,200\text{A}$, $L=100\text{nH}$, $T_j=125^\circ\text{C}$ |
| Turn On Loss | $E_{on(10\%)}$ | J/P | - | 1.6 | 2.1 | $V_{CC}=1,650\text{V}$, $I_C=1,200\text{A}$, $L=100\text{nH}$ |
| Turn Off Loss | $E_{off(10\%)}$ | J/P | - | 1.3 | 1.7 | $R_G=3.3\Omega$ (3) |
| Reverse Recovery Loss | $E_{rr(10\%)}$ | J/P | - | 1.2 | 1.9 | $V_{GE}=\pm 15\text{V}$, $T_j=125^\circ\text{C}$ |
| Stray inductance module | L_{SCE} | nH | - | 12 | - | |
| Thermal Impedance | IGBT | $R_{th(j-c)}$ | - | - | 0.0085 | Junction to case |
| | FWD | $R_{th(j-c)}$ | - | - | 0.017 | |
| Contact Thermal Impedance | $R_{th(c-f)}$ | K/W | - | 0.006 | - | Case to fin |

Notes:(3) R_G value is the test condition's value for evaluation of the switching times, not recommended value.Please, determine the suitable R_G value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted.

* Please contact our representatives at order.

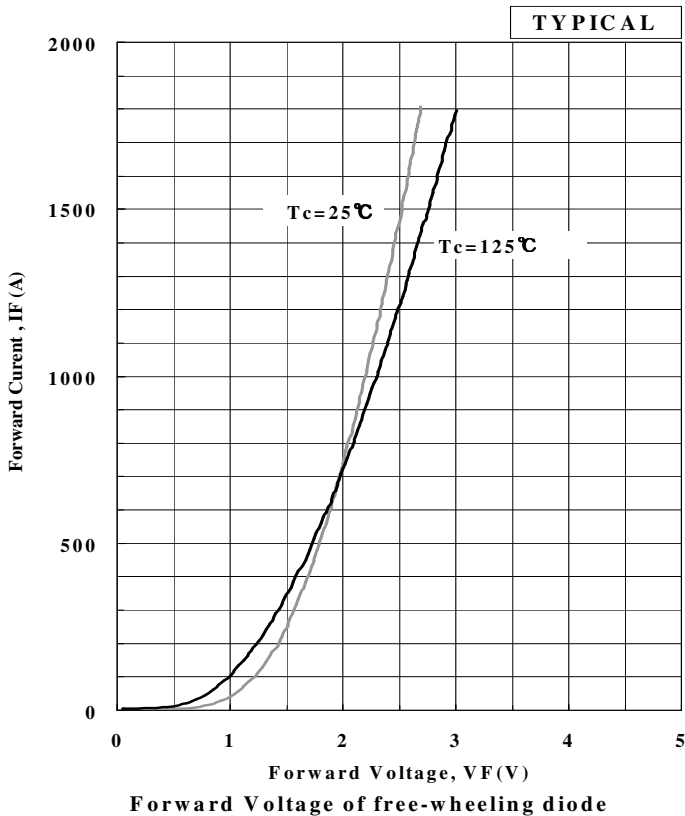
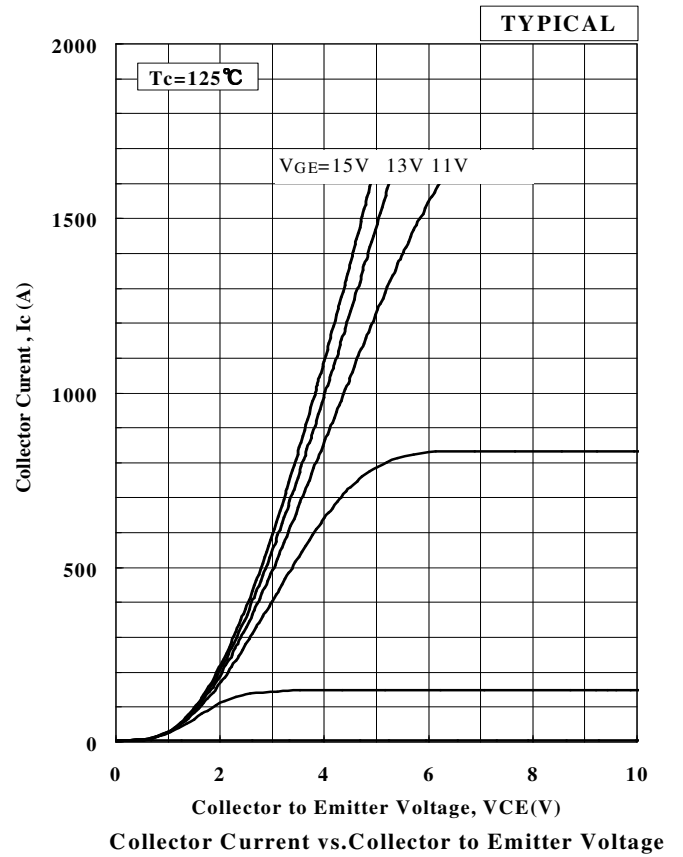
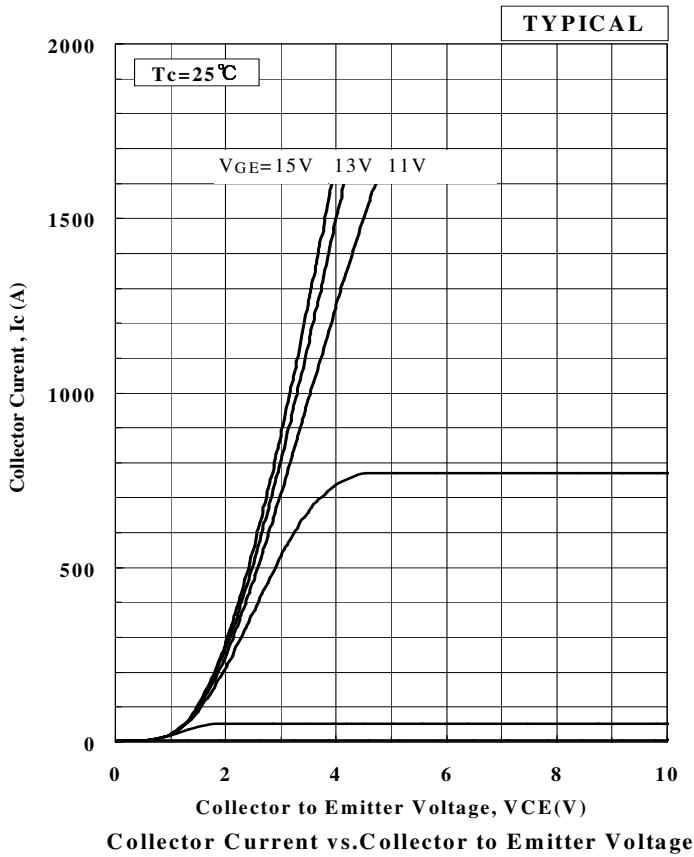
* For improvement, specifications are subject to change without notice.

* For actual application, please confirm this spec sheet is the newest revision.

MBN1200E33D

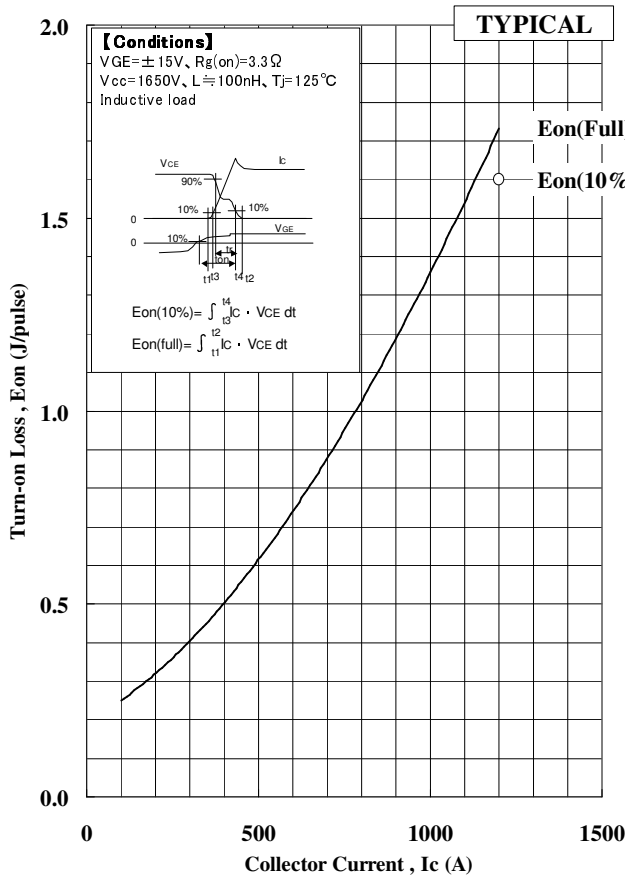
CHARACTERISTICS CURVE

STATIC CHARACTERISTICS

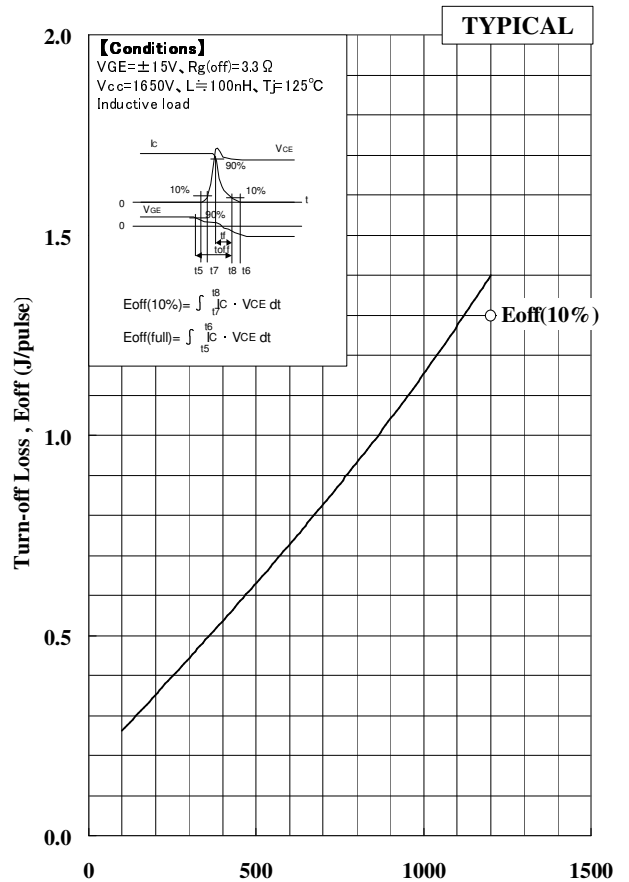


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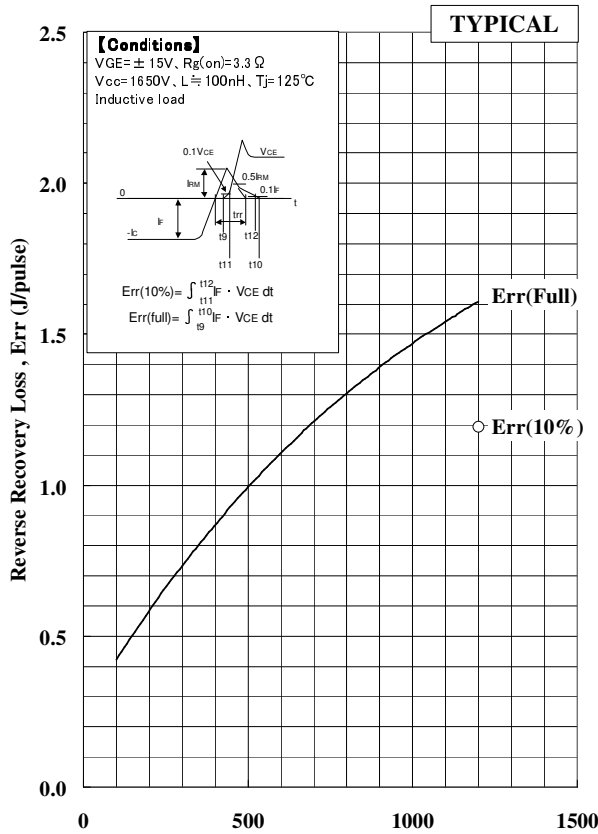
DEPENDENCE OF CURRENT



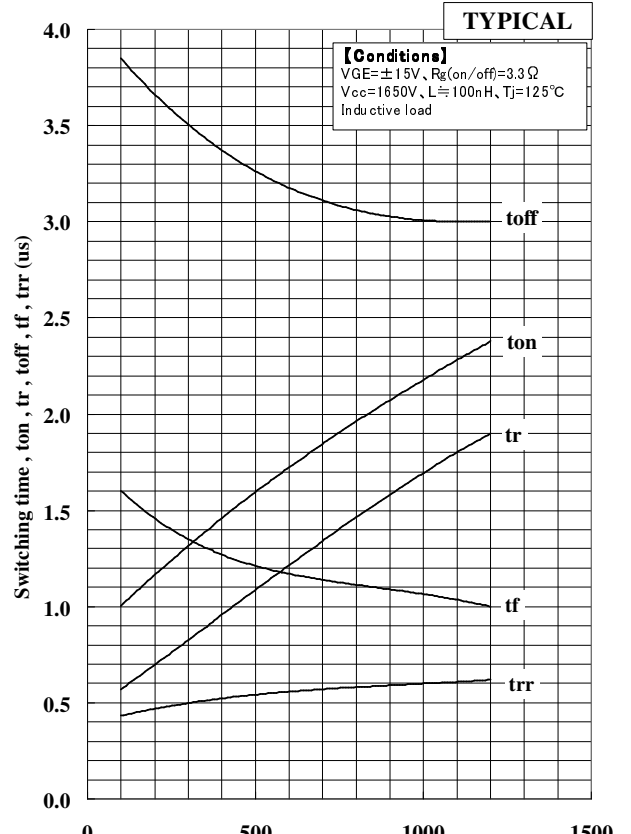
Turn-on Loss vs. Collector Current



Turn-off Loss vs. Collector Current



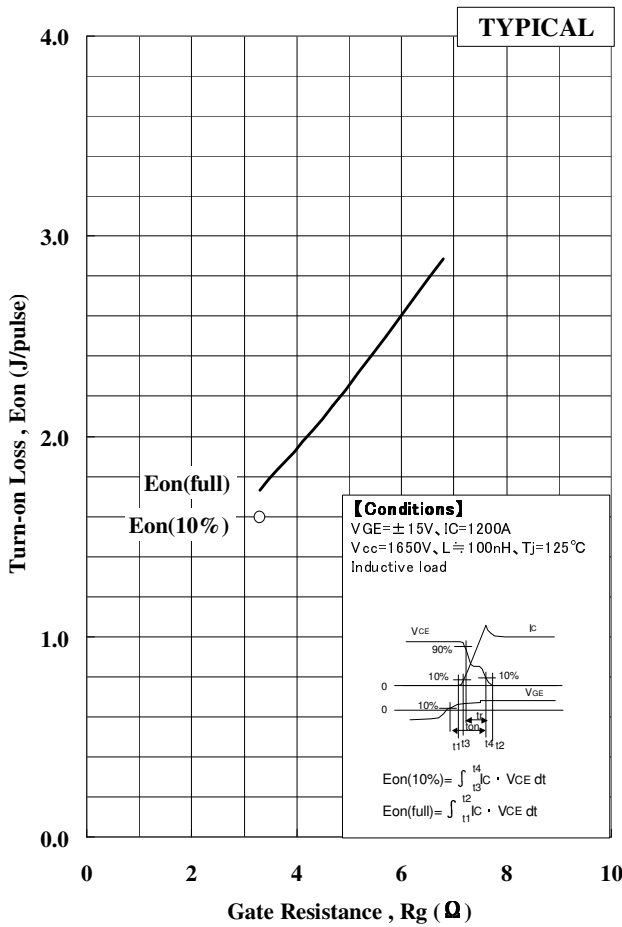
Recovery Loss vs. Forward Current



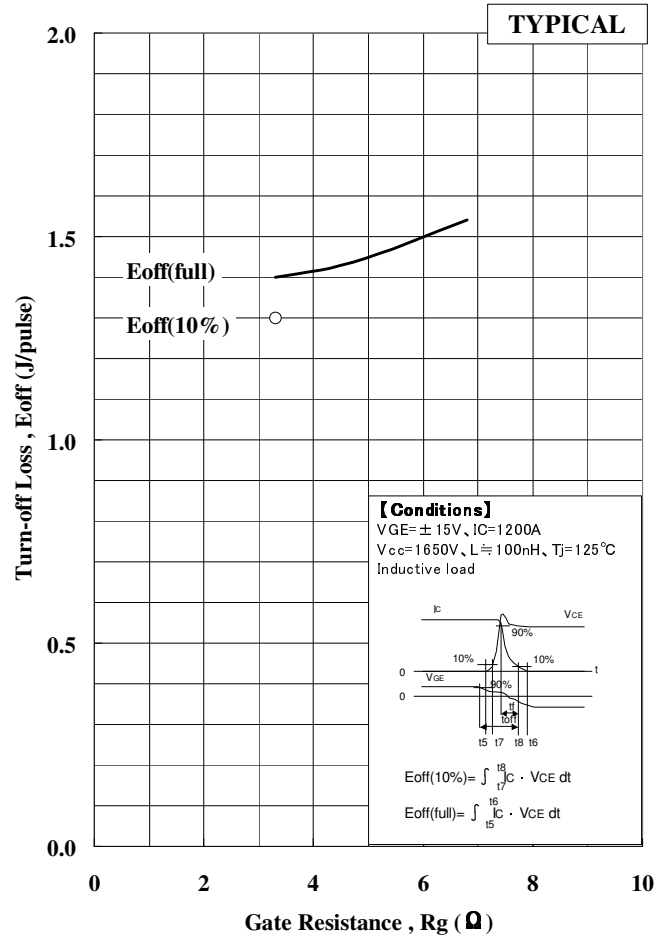
Switching time vs. Collector current

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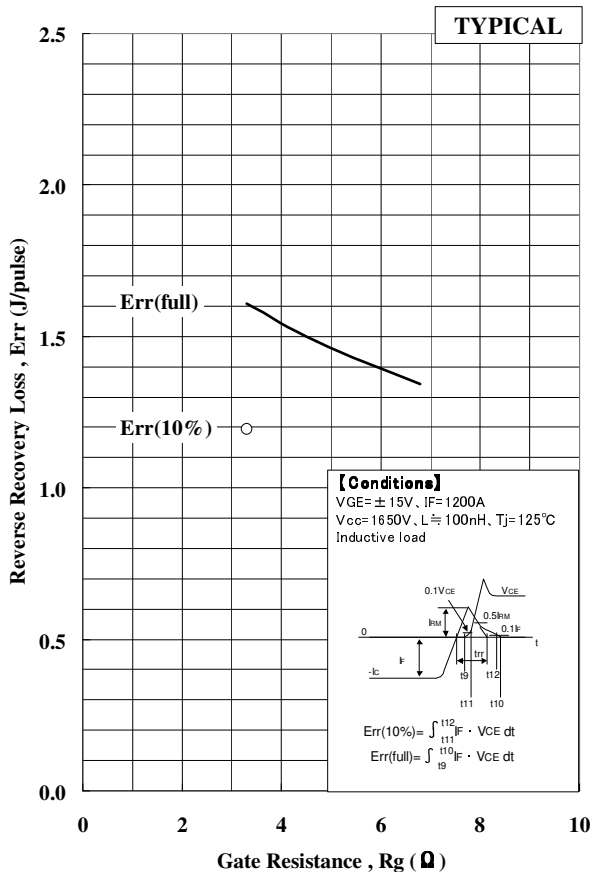
DEPENDENCE OF R_G



Turn-on Loss vs. Gate Resistance



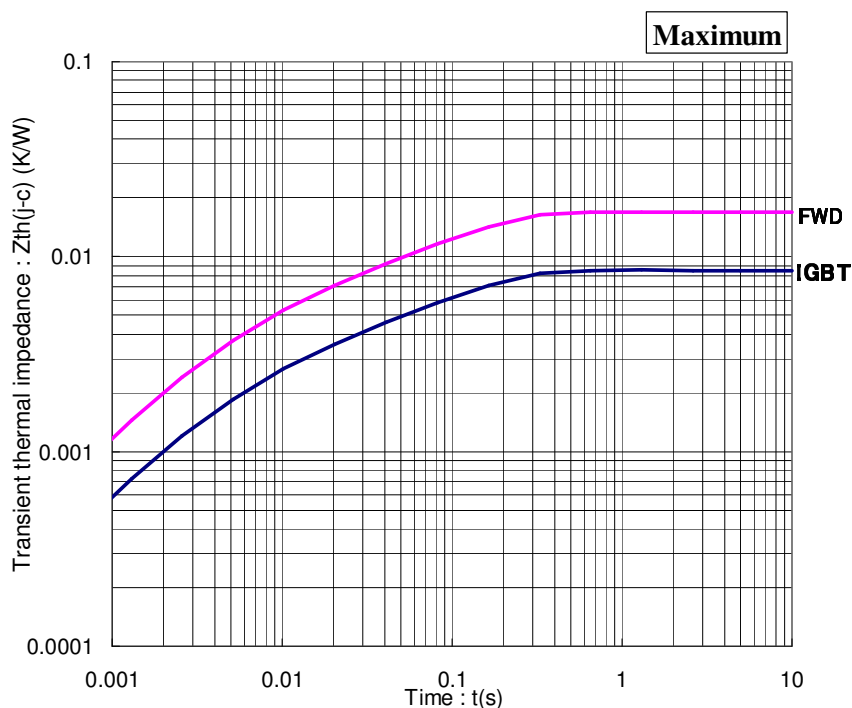
Turn-off Loss vs. Gate Resistance



Recovery Loss vs. Gate Resistance

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TRANSIENT THERMAL IMPEDANCE



Transient Thermal Impedance Curve

Negative environmental impact material

Please note the following negative environmental impact materials are contained in the product in order to keep product characteristic and reliability level.

| Material | Contained part |
|-----------------------------|----------------|
| Lead (Pb) and its compounds | Solder |
| Arsenic and its compounds | Si chip |

HITACHI POWER SEMICONDUCTORS

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